

## Sophisticated Analytical Instrument Facility, AIIMS, New Delhi

Sl. No.	Instrument	Make/ Model	Major Specifications/ Accessories available	Type of measurement/analysis available
1.	Scanning Electron Microscope	LEO 435 VP	Acc. voltage: 30 kV; Magnification: upto 3,00,000x; Image analyzer system; EDS	Study of surface topography/morphology of any sample including cells and tissues for research and diagnostic purposes. Analysis with low vacuum and image analysis facility.
2.	Transmission Electron Microscope	Philips CM 10	Acc. voltage: 100 kV; Magnification: upto 4,50,000x;	Study of the internal architecture of cells and tissues for research, diagnostic and teaching purposes.
3.	Transmission Electron Microscope	FEI Philips Morgagni 268D	Acc. voltage: 100 kV Magnification: upto 2,80,000x	TEM study as above with image analysis facility.
4.	Transmission Electron Microscope	FEI Tecnai S Twin	Acc. voltage: 200 kV Magnification: upto 10,30,000x	Study of the internal architecture of cells, tissues and nanomaterials with better resolution and software for 3d tomographic reconstruction.
5.	SEM Specimen preparation			Drying of biological samples.
	a. Critical Point Dryer	Jumbo		
	b. Critical Point Dryer			
	c. Sputter coater	Balzer SCD 020		Metal coating of biological samples.
6.	TEM Specimen preparation			Ultrathin sectioning of biological samples by conventional technique & cryotechnique
	a. Ultramicrotome	Leica Ultracut E		
	a. Ultramicrotome	Leica Ultracut UCT		
	b. Ultramicrotome	Leica Ultracut UC6		
	c. Vibrotome			Cutting thick sections to select area of interest for ultrastructural processing